Search Notes

Application/Control No	Applicant(s)/Patent und Reexamination	ter
09/855,511	CHEN ET AL.	
Examiner	Art Unit	
lana N Le	2685	

SEARCHED				
Class	Subclass	Date	Examiner	
455	127.1	7/26/2005	L.L.	
	127.2	,		
	127.3			
	115.1			
	115.3			
	115.4			
	343.1			
	343.2			
	343.5			
455	127.5			
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INTERFERENCE SEARCHED						
Cla	ess	Subclass	[Date	Exar	niner
45	55	127.1	7/26/2005		L.L.	
		127.3			1	
		343.1				
330	0	115.1 51				

SEARCH (INCLUDING SEAF		GY)
	DATE	
East-subclasses -keywords	7/26/200	05 L.L.
consulted with: Vo, Nguyen	7/26/200	05 L.L.
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